

Title (en)
METHOD AND APPARATUS FOR BUILT-IN SELF TEST OF INTEGRATED CIRCUITS

Title (de)
VERFAHREN UND APPARAT ZUM EINGEBAUTEN SELBSTTESTEN VON INTEGRIERTEN SCHALTUNGEN

Title (fr)
PROCEDE ET APPAREIL POUR AUTOCONTROLE DE CIRCUITS INTEGRES

Publication
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Application
EP 98945762 A 19980821

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US 9817298 W 19980821

Abstract (en)
[origin: WO0011674A1] A BIST function is provided in which both the row address (50) and the column address (40) of a memory (90) to be tested may be selected independently. The present invention provides flexibility in selecting address to be tested, improves transition time between rows, and allows determination of which memory address passes or fails the test.

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G11C 7/00 (2013.01 - KR); **G11C 29/18** (2013.01 - EP)

Citation (search report)

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- See references of WO 0011674A1

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